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37 C.F.R. § 1.8

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July 21, 2004  
Date

Mary Paul  
Signature

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:

KARSTEN WIECZOREK  
ROLF GEILENKEUSER  
JÖRG-OLIVER WEIDNER

Serial No.: 10/649,051

Filed: August 27, 2003

For: INTEGRATED SEMICONDUCTOR  
STRUCTURE FOR RELIABILITY  
TESTS OF DIELECTRICS

Group Art Unit: 2811

Examiner: Unknown

Atty. Dkt. No.: 2000.108400/DE0349

Customer No.: 23720

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed foreign patent documents and journal articles required by 37 C.F.R. § 1.98(a)(2) are enclosed for the convenience of the Examiner. Because the filing date of the present application is after June 30, 2003, copies of the listed U.S. patents are not included.

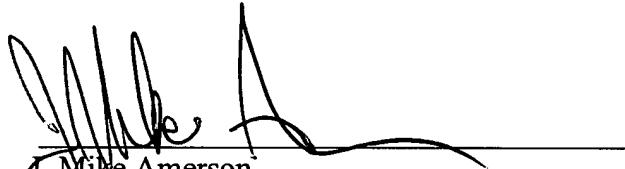
In accordance with 37 C.F.R §§ 1.97(g),(h), this Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R § 1.97(e)(1), Applicants hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the present statement, as evidenced by the date of the enclosed letter from our associate in Germany.

Applicants respectfully request that the listed documents be made of record in the present case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON  
CUSTOMER NUMBER 23720



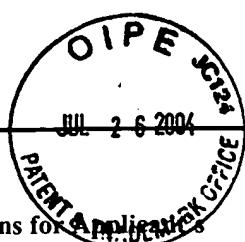
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ATTORNEY FOR APPLICANTS

Form PTO-1449 (modified)



Atty. Docket No. 2000.108400/DE0349	Serial No. 10/649,051
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**List of Patents and Publications for Application No. 10/649,051**

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Applicant Karsten Wieczorek, Rolf Geilenkeuser and Jörg-Oliver Weidner
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Filing Date: August 27, 2003	Group: 2811
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<b>U.S. Patent Documents</b> <i>See Page 1</i>	<b>Foreign Patent Documents</b> <i>See Page 1</i>	<b>Other Art</b> <i>See Page 1</i>
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### **U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A1	6,472,233 B1	10/29/02	Ahmed <i>et al.</i>	438	14	
	A2	2002/0033710 A1	3/21/02	Kim	324	765	
	A3						
	A4						
	A5						

### **Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1	DE 100 10 285 A1	9/13/01	Germany	H01L	23/544	No
	B2						
	B3						

### **Other Art (Including Author, Title, Date Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
	C1	Kim <i>et al.</i> , "Breakdown Phenomena in MIS Structure," <i>Proc. Of 3<sup>rd</sup> Int'l Conf. on Properties and Application of Dielectric Materials</i> , Tokyo, Japan, pp. 164-168, July 8-12, 1991.
	C2	Shanware <i>et al.</i> , "Reliability evaluation of HiSiON gate dielectric film with 12.8 Å SiO <sub>2</sub> equivalent thickness," <i>IEEE</i> , pp. 6.6.1-6.6.4, 2001.
	C3	Abadeer <i>et al.</i> , "Key measurements of ultrathin gate dielectric reliability and in-line monitoring," <i>IBM J. Res. Develop.</i> , 43:407-16, 1999.

**EXAMINER:****DATE CONSIDERED:**

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.